

ICR HH500-75 set

Near-Field Microprobe 200 kHz - 1 GHz



Short description

The probe is designed for a high-resolution measurement of magnetic near fields. With the ICR H probe the following measurements can be performed:

- Surface Scan via IC according to IEC 61967-3
- Volumenscan via IC
- Pin Scan

The measuring coil at the ICR RF probe head is horizontally aligned to the measurement surface. A preamplifier is integrated into the probe housing and powered by the Bias-Tee. The ICR near-field probes undergo a quality check before they are delivered. Different reference setup measurements are performed and resulting correction lines are generated. Two different correction lines are determined – a standardized correction line and an H-field correction line.

Attention: Due to its construction, the ICR probe is sensitive to shock and comes with a protective cap for transport and handling.

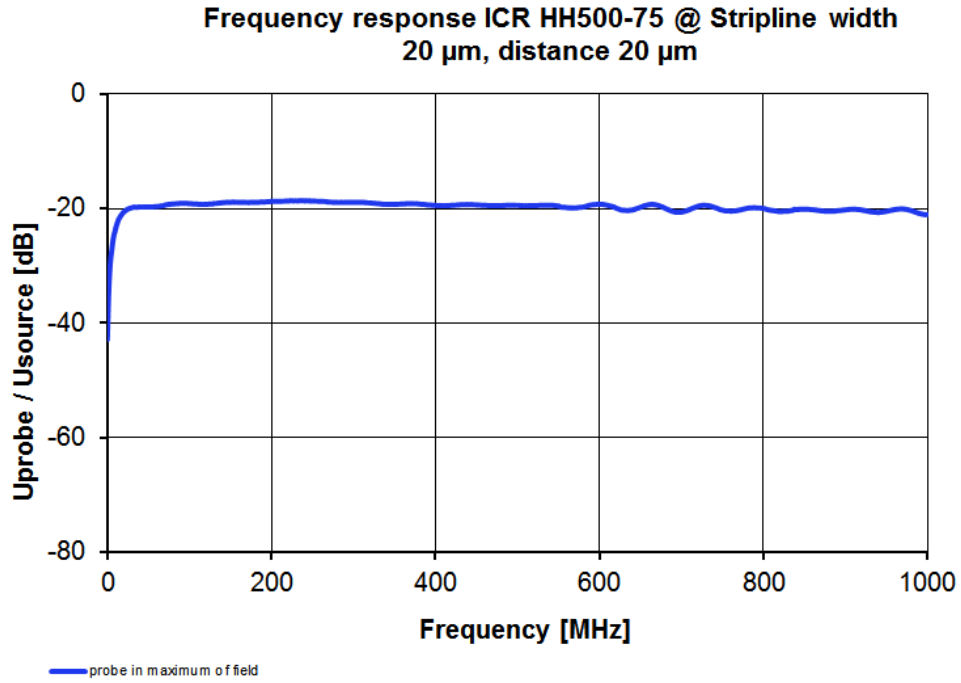
Scope of delivery

- 1x ICR HH500-75, Near-Field Microprobe 200 kHz to 1 GHz
- 1x BT 706, Bias Tee for Langer probes
- 1x SMA-SMA RA, Cable SMA-SMA, right angle
- 1x ICR-C, ICR Certificate
- 1x ICR Corr, Correction Curves ICR / USB
- 1x NT FRI EU, Power Supply Unit
- 1x ICR case1, System Case

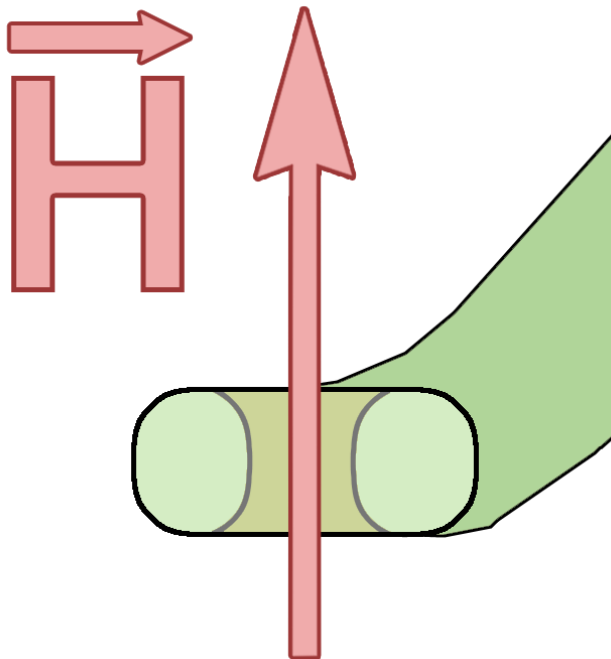
Technical parameters

Frequency range	200 kHz - 1 GHz
Resolution	300 µm
Internal diameter	500 µm

Frequency response

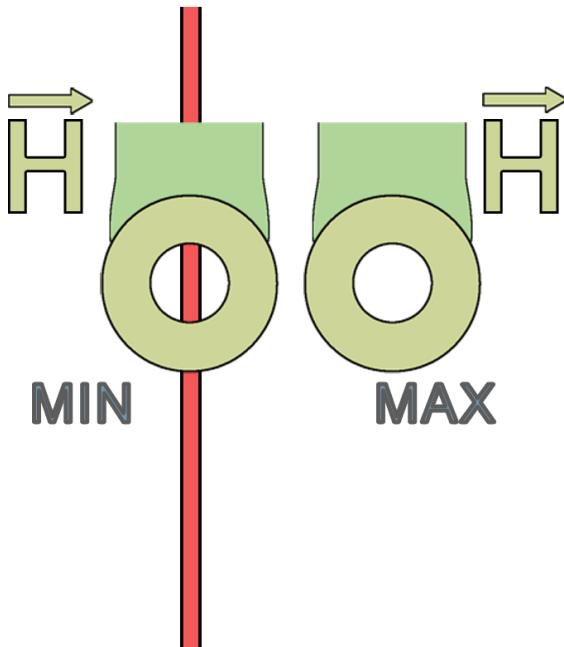


Measuring principles



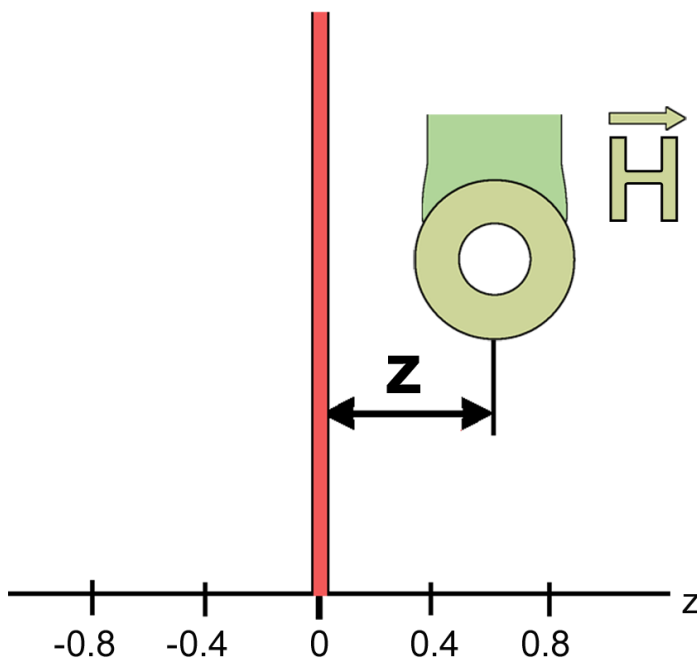
Design, view 1

Stripline



Design, view 2

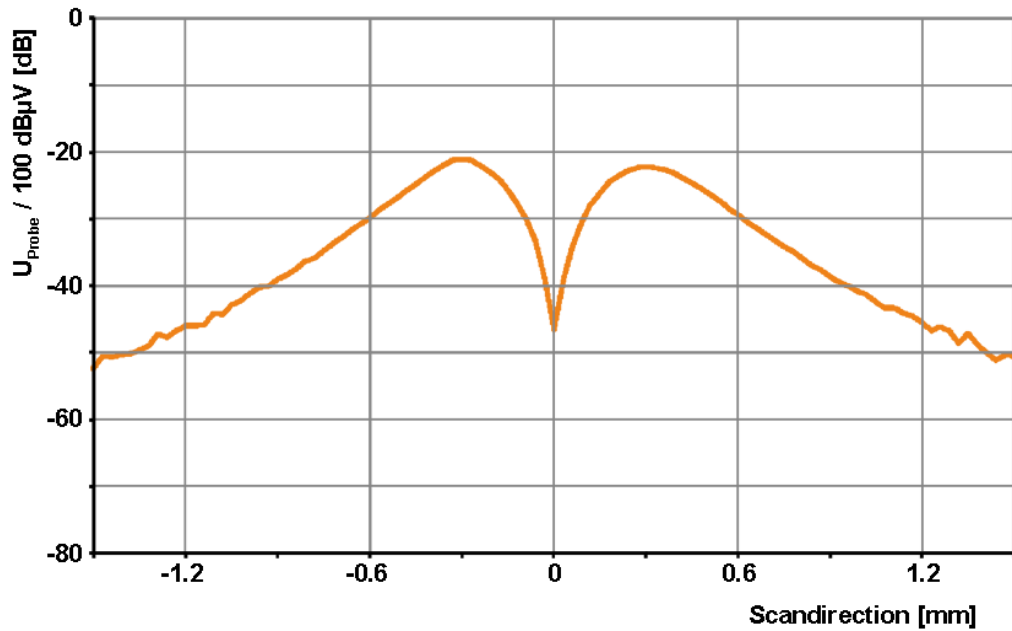
Stripline



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Transverse profile

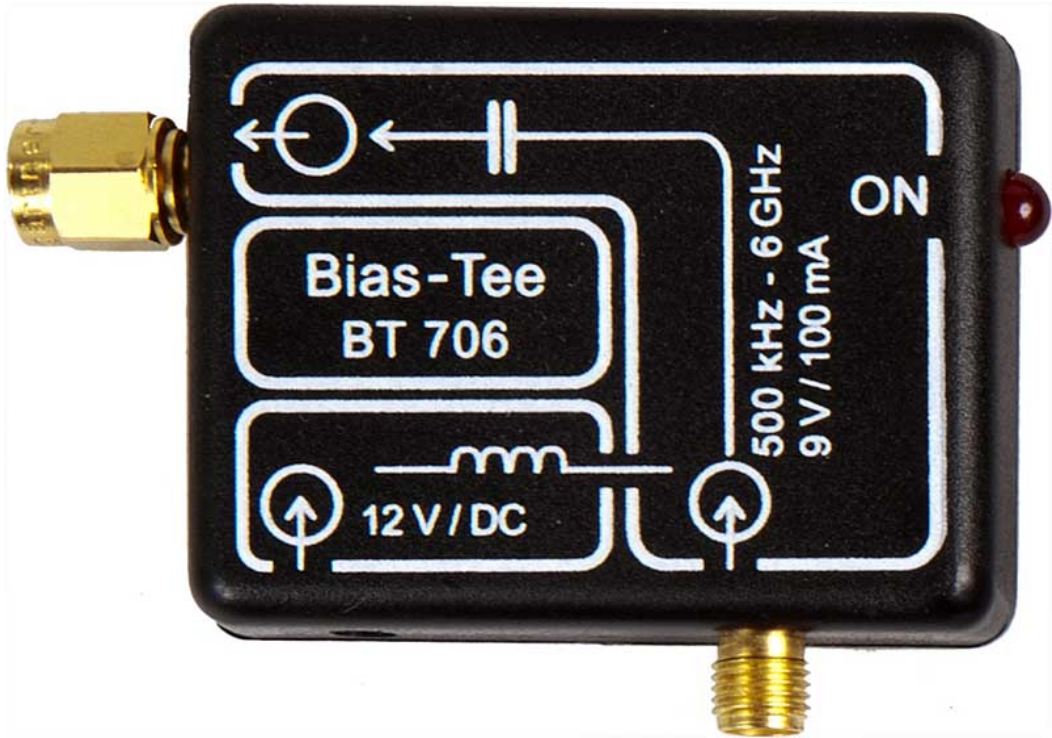


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